



InGaAs linear image sensors

G11508 series G11475 to G11478 series

Near infrared sensors (0.9 to 1.67 μ m/2.55 μ m)

The G11508/G11475 to G11478 series is an InGaAs linear image sensor designed for near infrared multichannel spectrophotometry. These linear image sensors consist an InGaAs photodiode array and charge amplifiers, offset compensation circuit, shift register, and timing generator formed on a CMOS chip. Charge amplifiers are configured with CMOS transistor array and are connected to each pixel of the InGaAs photodiode array. Since the signal from each pixel is read in charge integration mode, high sensitivity and stable operation are attained in the near infrared region. These sensors feature higher data rates and better linearity characteristics at high gain than the previous products. The package is hermetically sealed providing excellent reliability.

The signal processing circuit on the CMOS chip enables the selection of a conversion efficiency (CE) from the available two types using external voltage.

Features

- Low noise, low dark current
- Selectable from two conversion efficiency types
- Built-in saturation countermeasure circuit
- **■** Built-in CDS circuit*1
- **■** Built-in thermistor
- Easy operation (built-in timing generator*2)
- High resolution: 25 μm pitch (G11508-512SA, G11475 to G11478-512WB)

- Applications

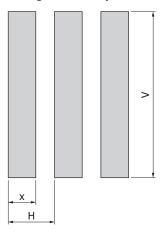
- Near infrared multichannel spectrophotometry
- **■** Radiation thermometers
- Non-destructive inspection equipment

- *1: On charge amplifiers, the reset noise that occurs when the integration capacitance is reset is dominant. However, the CDS circuit, which takes the difference between the signal after the completion of the integration time and the signal immediately after resetting, greatly reduces the reset noise.
- *2: Previously, multiple timing signals were applied using external PLDs or the like to run the shift register. This image sensor has a built-in CMOS circuit for timing generation. All timing signals are generated inside the image sensor by simply applying CLK and Reset signals.

Structure

Type no.	Cooling	Image size (mm)	Pi×el size $(H) \times (V)$ (μm)	Pixel pitch (µm)	Total number of pixels	Number of effective pixels	Fill factor	Package	Window material		
G11508-256SA	One-stage	12.8 × 0.5	50 × 500	50	256	256					
G11508-512SA	TE-cooled	12.6 × 0.5	25 × 500	25	512	512]				
G11475-256WB					50 × 250	50	256	256			
G11475-512WB			25 × 250	25	512	512		28-pin metal	Sapphire with AR		
G11476-256WB	Two stage		50 × 250	50	256	256	100				
G11477-256WB	Two-stage TE-cooled	12.8 × 0.25	50 × 250	50	256	256		metai	coating		
G11477-512WB	TE COOICG		25 × 250	25	512	512					
G11478-256WB			50 × 250	50	256	256					
G11478-512WB			25 × 250	25	512	512					

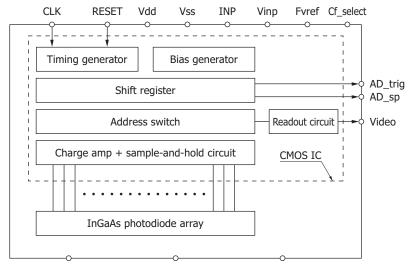
Enlarged view of photosensitive area



Number of pixels	х	Н	V
256	30	50	250
250	30	50	500
512	10	25	250
512	10	25	500

KMIRC0111EA

Block diagram



Thermoelectric cooler + Thermoelectric cooler - Temperature monitor

KMIRC0103E

- Absolute maximum ratings

Parameter	Symbol	Condition	Min.	Тур.	Max.	Unit
Supply voltage	Vdd, INP, Fvref Vinp, PDN	Ta=25 °C	-0.3	-	+6	V
Clock pulse voltage	Vclk	Ta=25 °C	-0.3	-	+6	V
Reset pulse voltage	V(res)	Ta=25 °C	-0.3	-	+6	V
Gain selection terminal voltage	Vcfsel	Ta=25 °C	-0.3	-	+6	V
Operating temperature*3	Topr	No dew condensation*4	-20	-	+70	°C
Storage temperature	Tstg	No dew condensation*4	-40	-	+85	°C

^{*3:} Chip temperature and package temperature

Note: Absolute maximum ratings indicate values that must not be exceeded. Exceeding the absolute maximum ratings even momentarily may cause a drop in product quality. Always be sure to use the product within the absolute maximum ratings.

➡ Recommended terminal voltage (Ta=25 °C)

Parameter		Symbol	Min.	Тур.	Max.	Unit	
Supply voltage		Vdd	4.7	5.0	5.3	V	
Differential reference vo	oltage	Fvref	1.1			V	
Video line reset voltage		Vinp	3.9	4.0	4.1	V	
Input stage amplifier reference voltage		INP	3.9	4.0	4.1	V	
Photodiode cathode voltage		PDN	3.9	4.0	4.1	V	
Ground		Vss	-	0	-	V	
Clock pulse voltage	High	Vclk	4.7	5.0	5.3	V	
Clock pulse voltage	Low	VCIK	0	0	0.4	1 V	
Reset pulse voltage	High	\/(xos)	4.7	5.0	5.3	V	
	Low	V(res)	0	0	0.3		

^{*4:} When there is a temperature difference between a product and the surrounding area in high humidity environment, dew condensation may occur on the product surface. Dew condensation on the product may cause deterioration in characteristics and reliability.

➡ Electrical characteristics (Ta=25 °C)

Parameter		Syr	nbol	Min.		Тур		M	lax.	Unit	
		I(Vdd)	256 ch	-		45			80		
			512 ch	-		85		1	120		
Current consumption		If\	/ref	-		-			1	mA	
Current Consumption		Iv	inp	-		-			1	IIIA	
		Ii	np	-		-			1		
	Ipdn		-	-		-		1			
Clock frequency		fe	fop 0.1 1				5	MHz			
Video data rate)R	0.1		fop			5	MHz	
Video output voltage	High	١	/н	-		4.0			-	V	
Video output voltage	Low	\	/L	-		1.2			-	_ v	
Output offset voltage	Output offset voltage		os	-		Fvre	f		-	V	
Output impedance		7	<u>′</u> o	-		5	5		-	kΩ	
AD_trig, AD_sp	AD_trig, AD_sp Pulse voltage High Low		ı, Vsp	-		Vdd			-	V	
Pulse voltage			i, vsp	-	·	GNE)		-		

■ Electrical and optical characteristics (Ta=25 °C, Vdd=5 V, INP=Vinp=PDN=4 V, Fref=1.2 V, Vclk=5 V, fop=1 MHz, CE=16 nV/e⁻)

Darameter	Cymbal	Condition	G	11508 series	*5	G1	.1475 to G	11478 series	*6	Unit
Parameter	Symbol	Condition	Min.	Тур.	Max.	Type no.	Min.	Тур.	Max.	Unit
						G11475	-	0.9 to 1.85	-	
Constant vacantas vacan	١,			0.0 += 1.67		G11476	-	0.9 to 2.05	-	l <u>.</u>
Spectral response range	λ		-	0.9 to 1.67	-	G11477	-	0.9 to 2.15	-	μm
						G11478	-	0.9 to 2.55	-	
Peak sensitivity wavelength λ			-			G11475	-	1.75	-	
	١٣			1.55		G11476	-	1.95	-	
	λр				-	G11477	-	1.95	-	μm
						G11478	-	2.3	-	
Photosensitivity		λ=λp 0.9		1.0		G11475	0.9	1.1	-	
	S		0.0			G11476	0.9	1.2	-	A/W
	5	Λ=ΛΡ	0.9	1.0	-	G11477	0.9	1.2	-	
						G11478	0.9	1.3	-]
Conversion efficiency*7	CE	Cf=10 pF	-	16	-		-	16	-	nV/e⁻
Conversion emiciency	CE	Cf=1 pF	-	160	-		-	160	-	nV/e⁻
Photoresponse nonuniformity*8	PRNU		-	±3	±5		-	±5	±10	%
Saturation output voltage	Vsat		2.7	2.8	-		2.7	2.8	-	V
Full well capacity	Csat	CE=16 nV/e ⁻	-	175	-		-	175	-	Me-
ruii weii capacity	Csat	CE=160 nV/e	-	17.5	-		-	17.5	-	Me
Readout noise*9	Nread	CE=16n V/e ⁻	-	200	400		-	200	400	μV rms
Reducut Hoise	INICau	CE=160 nV/e	-	300	500		-	400	500	μντιτιδ
Readout noise*10	Nread	CE=16 nV/e ⁻	-	-	-		-	220	500	μV rms
Reducut Hoise	IVICau	CE=160 nV/e ⁻	-	-	-		-	400	1000	μντιτισ
Dynamic range	Drange	*11	6750	14000	-		6750	14000	-	-
	Drange	*12	-	-	-		5400	12700	-	-
Defect pixels*13	-		-	-	0		-	-	5	%

^{*5:} Spectral response range: Tchip=-10 °C, other characteristics: Tchip=25 °C



^{*6:} Tchip=-20 °C

^{*7:} For switching the conversion efficiency, see the pin connections.

^{*8:} Measured at approximately 50% saturation and 10 ms integration time, pixel deviation after subtracting the dark output, excluding the first and last pixels

^{*9:} G11508 series: Integration time when CE=16 nV/e¯ is 10 ms. Integration time when CE=160 nV/e¯ is 1 ms. G11475 to G11477 series: Integration time when CE=16 nV/e¯ is 1 ms. Integration time when CE=160 nV/e¯ is 0.1 ms.

^{*10:} G11478 series: Integration time when CE=16 nV/e⁻ is 1 ms. Integration time when CE=160 nV/e⁻ is 0.1 ms.

^{*11:} G11508/G11475 to G11477 series

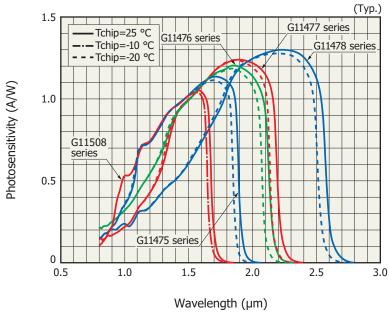
^{*12:} G11478 series

^{*13:} Pixels whose photoresponse nonuniformity, readout noise, or dark current is outside the specifications

□ Dark output characteristics (CE=16 nV/e⁻, G11508 series: Tchip=25 °C, G11475 to G11478 series: Tchip=-20 °C)

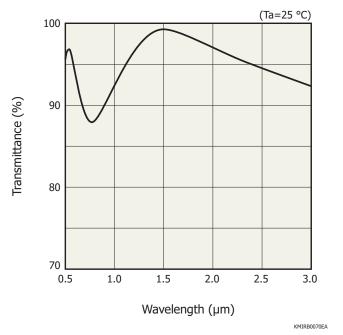
Para	meter	Symbol	Min.	Тур.	Max.	Unit	
	G11508-256SA		-1	±0.1	1		
	G11508-512SA		-0.5	±0.05	0.5		
Dark output (Dark output nonuniformity)	G11475-256WB		-2	±0.2	2		
	G11475-512WB		-2	±0.2	2		
	G11476-256WB	VD	-4	±0.4	4	V/s	
	G11477-256WB		-5	±0.5	5		
	G11477-512WB		-5	±0.5	5		
	G11478-256WB		-100	±10	100		
	G11478-512WB		-100	±10	100		
	G11508-256SA		-10	±1	10		
	G11508-512SA		-5	±0.5	5		
	G11475-256WB		-20	±2	20		
	G11475-512WB		-20	±2	20		
Dark current	G11476-256WB	ID	-40	±4	40	pА	
	G11477-256WB		-50	±5	50		
	G11477-512WB		-50	±5	50		
	G11478-256WB		-1000	±100	1000		
	G11478-512WB		-1000	±100	1000		

Spectral response

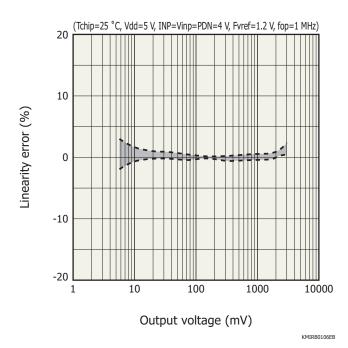


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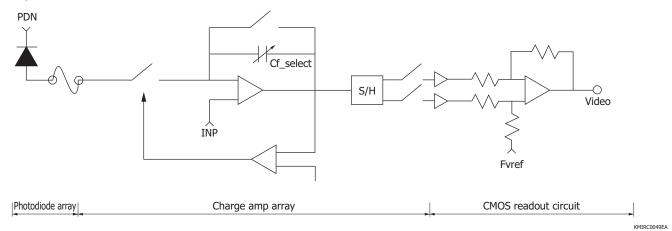
Spectral transmittance characteristics of window material (typical example)



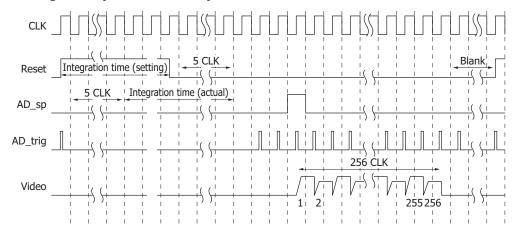
Linearity error (G11508 series, typical example)

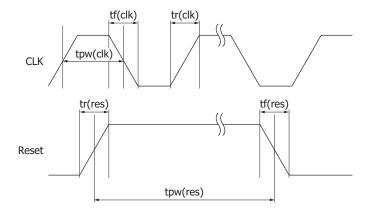


Equivalent circuit



Timing chart (each video line)

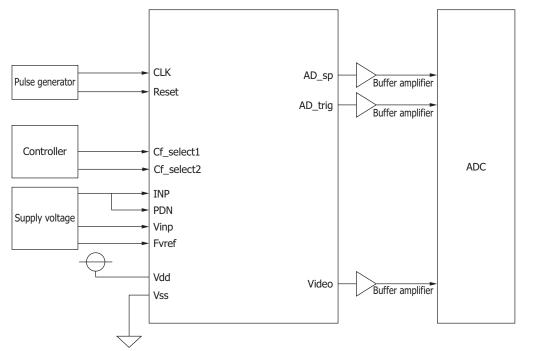




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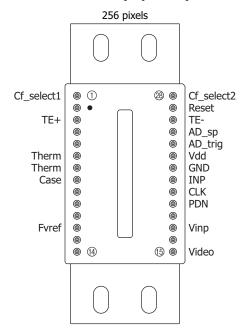
Parameter	Parameter		Min.	Тур.	Max.	Unit	
Clock pulse frequency	Clock pulse frequency		0.1	1	5	MHz	
Clock pulse width		tpw(clk)	60	500	5000	ns	
Clock pulse rise/fall times		tr(clk), tf(clk)	0	20	30	ns	
Reset pulse width	High	tow(roc)	6	-	-	clocks	
Reset puise width	Low	tpw(res)	284	-	-	clocks	
Reset pulse rise/fall times		tr(res), tf(res)	0	20	30	ns	

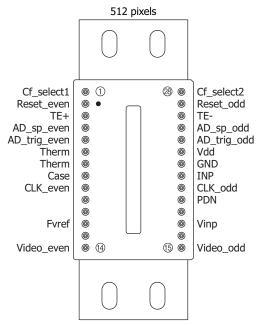
- Connection example



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Pin connections (top view)





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Terminal name	Input/ output	Function and recommended connection	Note
PDN	•	InGaAs photodiode's cathode bias terminal Set to the same potential as INP.	4.0 V
	Input	'	
AD_sp	Output	Digital start signal for A/D conversion	0 to 5 V
Cf_select1, 2	Input*14	Signal for selecting the feedback capacitance (integration capacitance) on the CMOS chip	0 V or 5 V
Thermistor	Output	Thermistor for monitoring the temperature inside the package	-
AD_trig	Output	Sampling sync signal for A/D conversion	0 to 5 V
Reset	Input	Reset pulse for initializing the feedback capacitance in the charge amplifier formed on the CMOS chip. Integration time is determined by the high level period of this pulse.	0 to 5 V
CLK	Input	Clock pulse for operating the CMOS shift register	0 to 5 V
INP	Input	Input stage amplifier reference voltage. This is the supply voltage for operating the signal processing circuit on the CMOS chip. Set to the same potential as PDN.	4.0 V
Vinp	Input	Video line reset voltage. This is the supply voltage for operating the signal processing circuit on the CMOS chip.	4.0 V
Fvref	Input	Differential amplifier reference voltage. This is the supply voltage for operating the signal processing circuit on the CMOS chip.	1.2 V
Video	Output	Differential amplifier output. This is an analog video signal.	1.2 to 4.0 V
Vdd	Input	Supply voltage (+5 V) for operating the signal processing circuit on the CMOS chip	5 V
GND	Input	Ground for the signal processing circuit on the CMOS chip (0 V)	0 V
Case	-	This terminal is connected to the package.	-
TE+, TE-	Input	Power supply terminal for the thermoelectric cooler for cooling the photodiode array	-

^{*14:} The conversion efficiency is determined by the supply voltage to the Cf_select terminal as follows.

Conversion efficiency	Cf_select1	Cf_select2
16 nV/e ⁻ (low gain)	High	High
160 nV/e⁻ (high gain)	High	Low

Low: 0 V (GND), High: 5 V (Vdd)

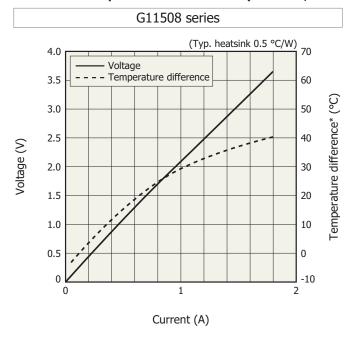
TE-cooler specifications (Ta=25 °C, Vdd=5 V, INP=Vinp=PDN=4 V, Fvref=1.2 V, Vclk=5 V, fop=1 MHz)

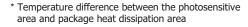
Parameter	Condition	Symbol	G11508 series			G11475 to G11478 series			Unit
Parameter	Condition		Min.	Тур.	Max.	Min.	Тур.	Max.	Offic
Allowable TE-cooler current		Ic max.	-	-	1.8	-	-	2.8	Α
Allowable TE-cooler voltage		Vc max.	-	-	5.0	-	-	4.0	V
Temperature difference*15	*16	ΔΤ	40	-	-	50	-	-	°C
Thermistor resistance		Rth	9	10	11	9	10	11	kΩ
Thermistor B constant	T1=25 °C, T2=-20 °C	В	-	3660	-	-	3660	-	K
Thermistor power dissipation		Pth	-	-	400	-	-	400	mW

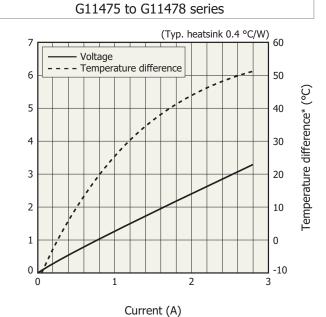
^{*15:} Temperature difference between the photosensitive area and package heat dissipation area

TE-cooler temperature characteristics (Ta=25 °C, Vdd=5 V, INP=Vinp=PDN=4 V, Fvref=1.2 V, Vclk=5 V, fop=1 MHz)

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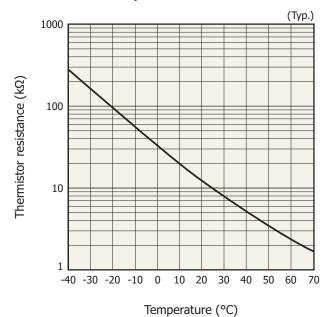
^{*} Temperature difference between the photosensitive area and package heat dissipation area

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^{*16:} One-stage TE-cooler: Ic=1.7 A, two-stage TE-cooler: Ic=2.6 A

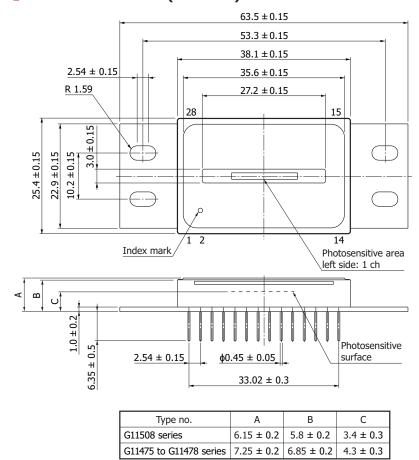
Thermistor temperature characteristics



Temperature (°C)	Thermistor resistance $(k\Omega)$	Temperature (°C)	Thermistor resistance $(k\Omega)$
-40	281	20	12.5
-35	208	25	10.0
-30	155	30	8.06
-25	117	35	6.53
-20	88.8	40	5.32
-15	68.4	45	4.36
-10	53.0	50	3.59
-5	41.2	55	2.97
0	32.1	60	2.47
5	25.1	65	2.07
10	19.8	70	1.74
15	15.7		

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► Dimensional outline (unit: mm)





Center accuracy of photosensitive area: ± 0.3 or less (with respect to package center)

Rotation accuracy of photosensitive area ±2° or less

(with respect to package center) Chip material: InGaAs

Package material: FeNi alloy Lead processing: Ni/Au plating Lead material: FeNiCo alloy Window material: Sapphire Window refractive index: 1.76 Window thickness: 0.66 AR coating: 1.55 µm peak Window sealing method: Brazing

Cap sealing: Welding

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Recommended soldering conditions

 \cdot Solder temperature: 260 °C max. (10 s or less, once)

Solder the leads at a point at least 1 mm away from the package body

Note: When you set soldering conditions, check that problems do not occur in the product by testing out the conditions in advance.

Electrostatic countermeasures

This device has a built-in protection circuit against static electrical charges. However, to prevent destroying the device with electrostatic charges, take countermeasures such as grounding yourself, the workbench and tools. Also protect this device from surge voltages which might be caused by peripheral equipment.

Related information

www.hamamatsu.com/sp/ssd/doc_en.html

- Precautions
- Disclaimer
- · Safety precautions
- · Image sensors
- Technical information
- · InGaAs linear image sensors / Technical note

Information described in this material is current as of October 2021.

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